

Title (en)

TEST VESSEL AND TEST ARRANGEMENT FOR A MONITORING DEVICE FOR VESSELS

Title (de)

TESTBEHÄLTNIS UND TESTANORDNUNG FÜR EINE KONTROLLVORRICHTUNG FÜR BEHÄLTNISSE

Title (fr)

RÉCIPIENT DE TEST ET INSTALLATION DE TEST POUR UN DISPOSITIF DE CONTRÔLE POUR RÉCIPIENTS

Publication

EP 2021780 A1 20090211 (DE)

Application

EP 07725004 A 20070509

Priority

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Abstract (en)

[origin: WO2007131673A1] The invention describes a method for examining workpieces in a spatially resolved and destruction-free manner using at least one measuring sensor which is guided over a technical surface of the workpiece to be examined and is able to detect local material inhomogeneities, local unsound areas of material and/or local material structures within the workpiece. The invention is distinguished by the fact that, proceeding from a starting position at which the at least one measuring sensor is positioned on the surface of the workpiece and a first volume region of the workpiece, which can be detected by the measuring sensor and is represented by a first measurement signal, is detected, a movement trajectory is determined, by moving the measuring sensor along the workpiece surface into a second position, on the basis of a comparison of the first measurement signal with a second measurement signal which is obtained at the second position and represents a second volume region, wherein the first and second volume regions at least partially overlap, and the relative position of the second position relative to the starting position on the surface of the workpiece is determined using the movement trajectory.

IPC 8 full level

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CPC (source: EP US)

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Citation (examination)

- US 5816029 A 19981006 - SWEENEY KEVIN M [US]
- US 4280612 A 19810728 - NAGANO YASUAKI

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Designated extension state (EPC)

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